

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination MIURA ET AL.	
			Examiner David N. Werner	Art Unit 2621	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0118243 A1	06-2003	Sezer et al.	382/245
*	B	US-2001/0036355 A1	11-2001	Kelly et al.	386/52
*	C	US-5,396,497 A	03-1995	Veltman, Markus H.	375/240.25
*	D	US-5,668,601 A	09-1997	Okada et al.	375/240.25
*	E	US-5,877,812 A	03-1999	Krause et al.	375/240.25
*	F	US-6,031,960 A	02-2000	Lane, Frank	386/68
*	G	US-6,034,731 A	03-2000	Hurst, Jr., Robert Norman	375/240.26
*	H	US-6,456,782 B1	09-2002	Kubota et al.	386/98
*	I	US-6,470,051 B1	10-2002	Campisano et al.	375/240.21
*	J	US-6,724,825 B1	04-2004	Nemiroff et al.	375/240.21
*	K	US-2002/0196850 A1	12-2002	Liu et al.	375/240.12
*	L	US-2003/0147561 A1	08-2003	Faibish et al.	382/245
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 798924 A2	10-1997	European Patent	ITO et al.	H04N 7/173
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.